The Suzaku/XIS: Calibration Status

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Outline

- E. Miller
 - instrument health and status
 - effective area (contamination) tracking and calibration
- B. LaMarr
 - changes in charge injection
- M. Nobukawa
 - CTI and gain correction
 - Si edge correction
- open issues

Suzaku/XIS - Overview

- 4 CCDs with independent X-ray telescopes (XRTs)
- 3 front-illuminated (FI) XIS0 XIS2 XIS3
 I back-illuminated (BI) XIS1



Field of view	17.8' x 17.8'
Energy range	0.2-12 keV
Energy resolution	~180 eV @6keV
Effective area	340 (FI)/390 (BI) cm ² @1.5keV
Time resolution	8 s (Normal) - 7.8 ms (Psum)

from Tsujimoto's "pocket guide"

Major XIS Events

2005 July 10	launch of Suzaku
2005 Aug 13	XIS doors open, start of observations
2006 Nov 9	anomaly (µ-meteorite?) in XIS2; 2/3 of chip affected, XIS2 switched off
2009 June 23	anomaly (µ-meteorite?) in XIS0; I/8 of chip affected, XIS0 safe for normal ops
2009 Dec 18	anomaly (µ-meteorite?) in XISI; no CCD damage, likely hole in XISI OBF
2011 June 1	XISI charge injection level raised for routine observations

XIS Status



from Tsujimoto's "pocket guide"

Molecular OBF Contamination

Effective Area Tracking



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from E0102

Contamination Model

- current model H,C,O
 - composition from RXJ1856
 - time-dependence from E0102
 - spatial dependence from bright Earth, Cygnus Loop
- new model H,C,N,O
 - composition, time dependence from E0102, RXJ1856, PKS2155
 - spatial dependence TBD
 - improve trend and improve composition

(Current) Contamination Model



from E0102

(Current) Contamination Model











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XIS1





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XIS1 Charge Injection Increase



- Since spaced row charge injection was implemented on board, the BI gain has evolved faster than the FI gains.
- The original BI injected charge level was below the FI level.

XIS Charge Injection



Massachusetts Institute of Technology

High Energy Response Improves

 Raising the injected charge level above the X-ray peak results in improved gain and resolution.

XIS1 Charge Injection Increase

• The current BI injected charge level results in performance evolution similar to the FI devices.

Massachusetts Institute of Technology

Calibration status of XIS Gain and Si-edge

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Charge Injection (CI) for Restore of Energy Resolution

- SCI (spaced-row charge injection) started on Sep. 2006.
- Slope of the gain degradation became flatter.
- Discrepancy of FI/BI ⇔ CI equiv. to 6 keV/2keV

CTI / Gain correction

Saw-tooth function of CTI: injected charges one charge injection per 54 rows 54 rows CTI correction in consideration of the saw-tooth shape 1640 1630 Pulse height (ch) TITI ITI 1620 1610 2007 2009 2011 1600 Readout Corrected Mn Kα @ 5.895 keV 1590 950 980 830 860 890 920 800 Line center energy (keV) 5.9 i (transfer number) Current status of energy scale after 5.85 CTI/gain correction Ne Heα @ 0.921 keV 0.95 Uncertainty of energy scale @6 keV @1 keV 0.9 \diamond XIS 1 XIS 3 FI (XISO/3) <6 eV <10 eV 500 1000 2000 <6 eV BI (XIS1) <10 eV Time after launch (days)

Modification of RMF for Si-edge Problem

- ~10% Residuals at ~1.84 keV (Si-edge)
- Negative/Positive for FI/BI
- We have tried to modify the Si-edge problem by various treatments
 - Neutral Si-K line
 - Energy resolution
 - => Unfortunately failed
- Semi-Phenomenological modifications with physical basis
 - -BI: Sub/Main intensity ratio
 - -FI: XAFS of Si-edge

BI: Discontinuous function of Sub/Main ratio at Si-edge

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BI: Discontinuous function of Sub/Main ratio at Si-edge

FI: XAFS of Si-edge

- Current QE model does not include XAFS.
- New model: XAFS => XAFS×3
 The residuals are significantly modified.

XIS Status - Summary

- 2.8 out of 4 detectors are operating normally
- charge injection change, Si edge modeling have greatly improved performance and calibration
- OBF contamination is the most pressing calibration issue

	X-RAY IMAGING SPECTROMETER (XIS) Instrument Monitoring											
MPO	CCD PERFORMANCE MONT	TORING										
π	Cal Source Monitoring	Using information from the Fe55 calibration source regions, we track the gain, spectral resolution, hot pixels, and CTI indicators. SCI-off and SCI-on data are monitored separately. These data have not processed by the calibration software.										
UE JETY BATYON	Monthly Cal Source Spectra	Spectra of integrated monthly Fe65 cal source data, by sensor and SCI setting.										
ORING Phote	INSTRUMENT HEALTH MONITORING											
	Instrument, HK Monitoring	Tracking of the CCD temperature, baseplate temperature, and TEC voltage.										
AXA	CCD Temperature Anomalies	Summary of anomalous temperature excursions for each detector.										
U. U.	CONTAMINATION MONITORIN	6										
u iwro	Point Source Monitoring	Tracking the on-axis OBF contamination with regular observations of soft point sources (primarily E0102).										
CLITY U AT ISAS T GSFC T TOOLO U.	Bright Earth Monitoring	Tracking the spatial dependence of the OBF contamination with monthly integrated observations of the sun-it Earth, which emits field filling C and N emission lines.										
	Wisses !!	HARDENDHISKITS INSULATE OF TEDHOLDAY										

	This leaflet is intended to assist the "Technical Description" doce	users to plan an ument supplemen	XIS observation. It the information.	The S Cons	iuzaku w sult <mark>xisop</mark>	eb pa e@as	ge (ht tro.isa	tp://w is.jaxa	ww.a a.jp for	stro.is furth	as.jaxa er deta	a.jp/su ails.	uzaku/	'index.	.html.	en) ar	d	
Rasics XIS is equipped with four X-ray		Field of view 17.8' x 17.8'			Aim point Choose either XIS- or HXD-no					iomin	al	Position	n	Normalized rate				
CCDs (XIS0-3) for imaging and	Energy range	ergy range 0.2-12 keV			position, depending on which										XIS		HXD	
non-dispersiv	e spectroscopy. The four CCDs are	Energy range	100 -14 @(1-14		detector you emphasize. The count rate differs by v10% Positions other than these may be useful XIS nominal 1									0.9				
observe the	ame field. Three CCDs are front-	Energy resolution ~180 eV @6keV			for map	ping o	bserva	ations		SC IIIO	y be u	Sciul	н	XD nom	ninal	0.9		1
illuminated (F1) and one is back-illuminated (B1) superior respectively in the hard- and soft-band. XIS is operated simultaneously with HXD.		Effective area 340 (FI)/390 (BI) cm ² @1 5keV																
		Time resolution	8 s (Normal) - 7.8 ms (Psum)		Clock	OCKING XIS is operated in a combination of clocking and editing modes. Users are responsible to choose the appropriate clocking mode. It icceptable to use different clocking modes for different sensors. For faint (<12												
Archive	Accepted targets : http://heasarc.c XIS log : http://darts.isas.jaxa.jp/a Obs plan : http://www.astro.isas.ja	gsfc.nasa.gov/doc astro/suzaku/suza axa.jp/suzaku/sch	s/suzaku/tlminfo/ akuxislog/top.do edule/shortterm/		[/s/sens point-lik options.	or]) s e sour For h	ources ces, c igh tin	s, use hoose ning a	Norma Norma Iccuraci	al moo al mo cy, cho	de with de with bose Ps	h app Sum (ption. ropria XIS3)	For bite win and of	right (dow a thers	(>12 [and/or (XIS0,	s/sens burst 1).	or])
View XIS0-3 has 1024x1024 pixels composed of four segments (A-D) with one readout node for each segment. Due to unavoidable micro-			Cloc	ck mode						Norr	mal						Psu	
			Ont	Win.	no	1/4	1/8	no	no	no	no	1/4	1/4	1/4	1/4	1/8	no	
(Psum) are not usable. Two [®] Fe calibration sources (Mn I Ka; and Kβ lines at 5.9 and 6.5 keV) are installed. Users can specify the roll angle. Use the Maki tool. (pixel) Unusable regions [®] Fe calibration Pixels to be				ion	Burst	no	no	no	2.0	0.7	0.5	0.1	1.0	0.5	0.3	0.1	0.5	no
				Max	cnt/s to					1.3	1.9	7.1		1.9	3.2	7.1	1.9	1.5
				avoid	l pile-up"	12	48	96	48	10 ²	10 ²	10 ²	96	10 ²	10 ²	10 ²	10 ²	10
124 512	150 70 OBF hole sources	read first. 17.8'			s rate %	2	7	14	76	91	94	98	54	77	86	94	57	0
				Su	upport	ОК	OK	*2	OK	*3	*3	*2	ОК	ОК	*2	*2	*2*5	*2*
D € ≭B		€×B A 17.8	*1:1 *2:0	The rates a Calibration Window the aim p The obse	rates are "hard limits". A 5-10% margin should be considered. Annulus extractions can also work, bination not guaranteed. "3: BI only, "4: FI only, "5: HXD-nominal only, ndow_option $1/n (n=4 \text{ or } 8)$ option reads ($1024t(1024/n)$) pixels centered at a im position in $8/n$ [s]. (Pros) Photons not lost for the observed area. (Cons) e observed area reduced by $1/n$. The calibration sources not observed.													
XISO (F	I) (51 YIS1 (BI) YIS2	(FI) XI	S3 (FT)	- E	Burst opt	<u>tion</u>	<i>m</i> [s]] (m=	0.1, 0.	3, 0.5	, 0.7, 2	2.0) o	ption	reads	photo	ns arr	iving ir	ı m
/130 (1	XIS nominal position	K HXD nominal positi	ion Roll		DUT Of 8	[S] IN ion an	each i ea not	mage redu	. (Pros) the	Calibra A fract	ion (1	SOURCE	S ODS	erved	. Ine		
Size of 90% en radius of a p	circled energy pint source		- → ⊬ R.A.	1	Psum mr	nde	128 n	nws a	re sta	ked a	ilona tł	he rea	adout	directi	on vi	eldina	(1024	x8)
Counte/c	Estimate the count rate using the	PIMMS tool. Appr	oximately,	; [pixel data (Cons) S	a. (Pro patial	os) Hig inforn	gh tim nation	ling ac	curac long t	y; 7.8 r he rea	ns in dout (record directi	ding evon. Sp	vent a vectra	irrival I perfr lity of	time. omanc	e

http://space.mit.edu/XIS/monitor

http://www.astro.isas.jaxa.jp/~tsujimot/pg_xis.pdf